

BRITISH STANDARDS INSTITUTION

2 PARK STREET, LONDON, W1A 2BS

Specification available from:- AS SHOWN IN PD 9002
AND CECC 00 200 AND

MOTOROLA LTD,
KELVIN ESTATE,
EAST KILBRIDE.
G75 0TG

BS CECC 90 104 - 223

ISSUE 1

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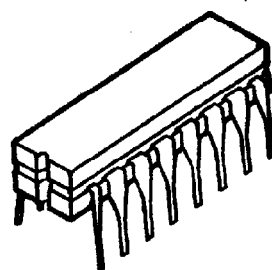


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ELECTRONIC COMPONENTS OF ASSESSED QUALITY
DETAIL SPECIFICATION IN ACCORDANCE WITH:

BS CECC 90 000 : 1982
BS CECC 90 100 : 1983

Outline not to scale: Isometric projection
Marking information see page 9



For detail dimensions see IEC 191-2 (A50C)

MANUFACTURERS TYPE NUMBER

4558B

SEE PD 9002 AND CECC 00 200
For ordering information
see page

BCD TO SEVEN SEGMENT DECODER

SILICON COMPLEMENTARY MOS.
WITH (B) BUFFERED OUTPUTS AND
CAVITY PACKAGING.

Assessment levels
R, T and V
and optional screening
categories A, B, C and D

CAUTION: THESE ARE STATIC SENSITIVE DEVICES - See clause 1.11

1. Limiting conditions of use (not for inspection purposes)

All voltages referenced to V_{SS}

1.1	Maximum supply voltage, positive	V_{DD}	+18,0 V
1.2	Maximum supply voltage, negative	V_{DD}	-0,5 V
1.3	Maximum positive input voltage	V_{IN}	$V_{DD} + 0,5 V$
1.4	Maximum negative input voltage	V_{IN}	-0,5 V

Refer to Qualified Products List PD 9002 and/or CECC 00 200
for details of manufacturers approved to this specification

1. Limiting conditions of use (contd)

1.5	Maximum power dissipation, per package	P_{D1}	936 mW
	per output	P_{D2}	117 mW
1.6	Maximum continuous current into any input.	$ I_I $	10,0 mA
1.7	Maximum continuous current into any output.	$ I_O $	10,0 mA
1.8	Operating temperature range	T_{amb}	
		Full	-55 to +125 °C
		Limited	-40 to +150 °C
1.9	Storage temperature range	T_{stg}	-65 to +150 °C
1.10	Transient energy rating		400 V at 100 pF through 1,5 kΩ

1.11 Recommended handling precautions

- 1.11.1 Store devices in either conductive foam or conductive rails, or connect all leads together using a similar electrical shorting method.
- 1.11.2 Use grounded tip soldering irons.
- 1.11.3 Ground all test equipment.
- 1.11.4 Connect all unused device inputs to V_{DD} or V_{SS} .
- 1.11.5 PC boards used to mount MOS devices should have all metal leads grounded during device mounting or flow soldering operations.
- 1.11.6 Soldering equipment, solder pots or flow soldering equipment should be grounded whenever in contact with PC boards and/or MOS devices.
- 1.11.7 Do not use ungrounded automatic insertion equipment or other handling equipment that precludes the use of suitable device lead grounding techniques during inspection or handling.
- 1.11.8 When PC boards containing mounted MOS devices are removed from equipment for test, shipping or storage, 'Dummy connectors' should be used to electrically short all PC board terminals together.
- 1.11.9 Switch off power supply before inserting or removing devices from circuits.
- 1.11.10 Disconnect all low impedance equipment and input signals from the device before d.c. power supplies are switched off.

2. Recommended conditions of use and associated characteristics (not for inspection purposes)

These apply over the operating temperature range unless otherwise stated. All voltages referenced to V_{SS} .

Characteristics	Conditions	Symbol	$V_{DD}(V)$	T_{amb} LOW	T_{amb} = 25 °C	T_{amb} HIGH	Unit
Quiescent device current	$V_{IL} = 0 V$ $V_{IH} = V_{DD}$						
Full temperature range	Outputs open circuit	I_{DDA}	5,0	5,0	5,0	150,0	μA
		I_{DDA}	10,0	10,0	10,0	300,0	μA
		I_{DDA}	15,0	20,0	20,0	600,0	μA
Limited temperature range		I_{DDA}	5,0	20,0	20,0	150,0	μA
		I_{DDA}	10,0	40,0	40,0	300,0	μA
		I_{DDA}	15,0	80,0	80,0	600,0	μA
LOW level output voltage at $ I_O < 1,0 \mu A$	$V_{IL} = 0 V$ $V_{IH} = V_{DD}$	V_{OLA}	5,0	0,05	0,05	0,05	V
		V_{OLA}	10,0	0,05	0,05	0,05	V
		V_{OLA}	15,0	0,05	0,05	0,05	V
HIGH level output voltage at $ I_O < 1,0 \mu A$	$V_{IL} = 0 V$ $V_{IH} = V_{DD}$	V_{OHB}	5,0	4,95	4,95	4,95	V
		V_{OHB}	10,0	9,95	9,95	9,95	V
		V_{OHB}	15,0	14,95	14,95	14,95	V
LOW level output voltage (for worst case combinations) at $ I_O < 1,0 \mu A$	$V_{IL} = 1,5 V$	V_{OLA}	5,0	0,5	0,5	0,5	V
	$V_{IL} = 3,0 V$	V_{OLA}	10,0	1,0	1,0	1,0	V
	$V_{IL} = 4,0 V$	V_{OLA}	15,0	1,5	1,5	1,5	V
HIGH level output voltage (for worst case combinations) at $ I_O < 1,0 \mu A$	$V_{IH} = 3,5 V$	V_{OHB}	5,0	4,5	4,5	4,5	V
	$V_{IH} = 7,0 V$	V_{OHB}	10,0	9,0	9,0	9,0	V
	$V_{IH} = 11,0 V$	V_{OHB}	15,0	13,5	13,5	13,5	V

Characteristics	Conditions	Symbol	$V_{DD}(V)$	T_{amb} LOW	T_{amb} = 25 °C	T_{amb} HIGH	Unit
Output LOW (sink) current							
Full temperature range	$V_O = 0,4 V$	I_{OLB}	5,0	0,64	0,51	0,36	mA
	$V_O = 0,5 V$	I_{OLB}	10,0	1,60	1,30	0,90	mA
	$V_O = 1,5 V$	I_{OLB}	15,0	4,20	3,40	2,40	mA
Limited temperature range	$V_O = 0,4 V$	I_{OLB}	5,0	0,52	0,44	0,36	mA
	$V_O = 0,5 V$	I_{OLB}	10,0	1,30	1,10	0,90	mA
	$V_O = 1,5 V$	I_{OLB}	15,0	3,60	3,00	2,40	mA
Output HIGH (source) current							
Full temperature range	$V_O = 4,6 V$	$-I_{OHB}$	5,0	0,64	0,51	0,36	mA
	$V_O = 9,5 V$	$-I_{OHB}$	10,0	1,60	1,30	0,90	mA
	$V_O = 13,5 V$	$-I_{OHB}$	15,0	4,20	3,40	2,40	mA
Limited temperature range	$V_O = 4,6 V$	$-I_{OHB}$	5,0	0,52	0,44	0,36	mA
	$V_O = 9,5 V$	$-I_{OHB}$	10,0	1,30	1,10	0,90	mA
	$V_O = 13,5 V$	$-I_{OHB}$	15,0	3,60	3,00	2,40	mA
Input leakage current	$V_{IL} = 0 V$ $V_{IH} = V_{DD}$						
Full temperature range		I_{IA}	15,0	0,10	0,10	1,00	μA
Limited temperature range		I_{IA}	15,0	0,30	0,30	1,00	μA
Input capacitance per unit load (Any input)	$V_I = 0 V$ $f = 1 MHz$	C_{IA}	-	-	7,5	-	pF
Noise margin at LOW level output (equal to the difference between V_{IL} and V_{OL} for worst case combinations)		V_{NLB}	5,0	1,0	1,0	1,0	V
		V_{NLB}	10,0	2,0	2,0	2,0	V
		V_{NLB}	15,0	2,5	2,5	2,5	V

Characteristics	Conditions	Symbol	$V_{DD}(V)$	T_{amb} LOW	T_{amb} = 25 °C	T_{amb} HIGH	Unit
Noise margin at HIGH level output (equal to the difference between V_{IH} and V_{OH} for worst case combinations)		V_{NHB}	5,0	1,0	1,0	1,0	V
		V_{NHB}	10,0	2,0	2,0	2,0	V
		V_{NHB}	15,0	2,5	2,5	2,5	V
Propagation and Transition Times	$C_L = 50$ pF (Test conditions as in Sub-group A5)						
Propagation Delay Time LOW to HIGH level BCD input to any segment		t_{PLHA}	5,0	-	1160,0	-	ns
			10,0	-	440,0	-	ns
			15,0	-	230,0	-	ns
Propagation Delay Time HIGH to LOW level BCD input to any segment		t_{PHLA}	5,0	-	1560,0	-	ns
			10,0	-	550,0	-	ns
			15,0	-	370,0	-	ns
Transition Time LOW to HIGH level		t_{TLHA}	5,0	-	200,0	-	ns
			10,0	-	100,0	-	ns
			15,0	-	80,0	-	ns
Transition Time HIGH to LOW level		t_{THLA}	5,0	-	200,0	-	ns
			10,0	-	100,0	-	ns
			15,0	-	80,0	-	ns
Total Supply Current		I_T	5,0	$I_T = (1,2\mu A/kHz)f + I_{DD}$			μA
			10,0	$I_T = (2,4\mu A/kHz)f + I_{DD}$			μA
			15,0	$I_T = (3,6\mu A/kHz)f + I_{DD}$			μA

Terminal identification

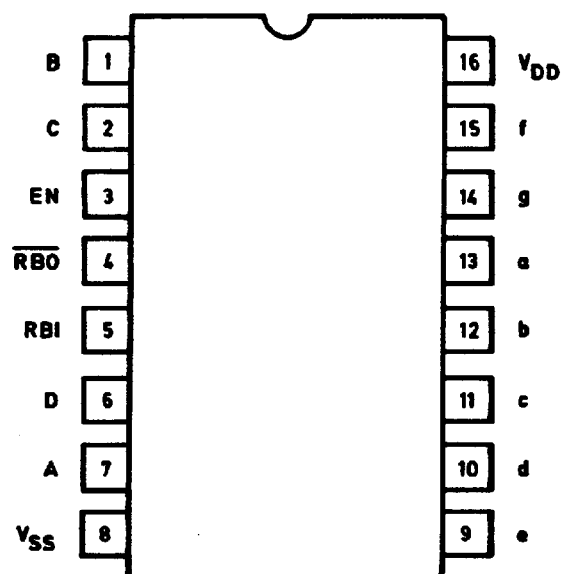


Figure 1

Function Table

Table 1

INPUTS						OUTPUTS *								
En Pin 3	$\overline{\text{RBI}}$ Pin 5	D Pin 6	C Pin 2	B Pin 1	A Pin 7	a Pin 13	b Pin 12	c Pin 11	d Pin 10	e Pin 9	f Pin 15	g Pin 14	$\overline{\text{RBO}}$ Pin 4	DISPLAY
H	H	L	L	L	L	H	H	H	H	H	H	L	H	0
H	X	L	L	L	H	L	L	L	L	H	H	L	H	1
H	X	L	L	H	L	H	H	L	H	H	L	H	H	2
H	X	L	L	H	H	H	H	H	H	L	L	H	H	3
H	X	L	H	L	L	L	H	H	L	L	H	H	H	4
H	X	L	H	L	H	H	L	H	H	L	H	H	H	5
H	X	L	H	H	L	L	L	H	H	H	H	H	H	6
H	X	L	H	H	H	H	H	H	L	L	L	L	H	7
H	X	H	L	L	L	H	H	H	H	H	H	H	H	8
H	X	H	L	L	H	H	H	H	L	L	H	H	H	9
H	L	L	L	L	L	L	L	L	L	L	L	L	L	Blank
L	L	X	X	X	X	H	H	H	H	H	H	H	L	Blank
L	H	X	X	X	X	L	L	L	L	L	L	L	H	Blank

* All non-valid BCD input codes produce a blank display.

H = High level

L = Low level

X = Level irrelevant

Logic diagram

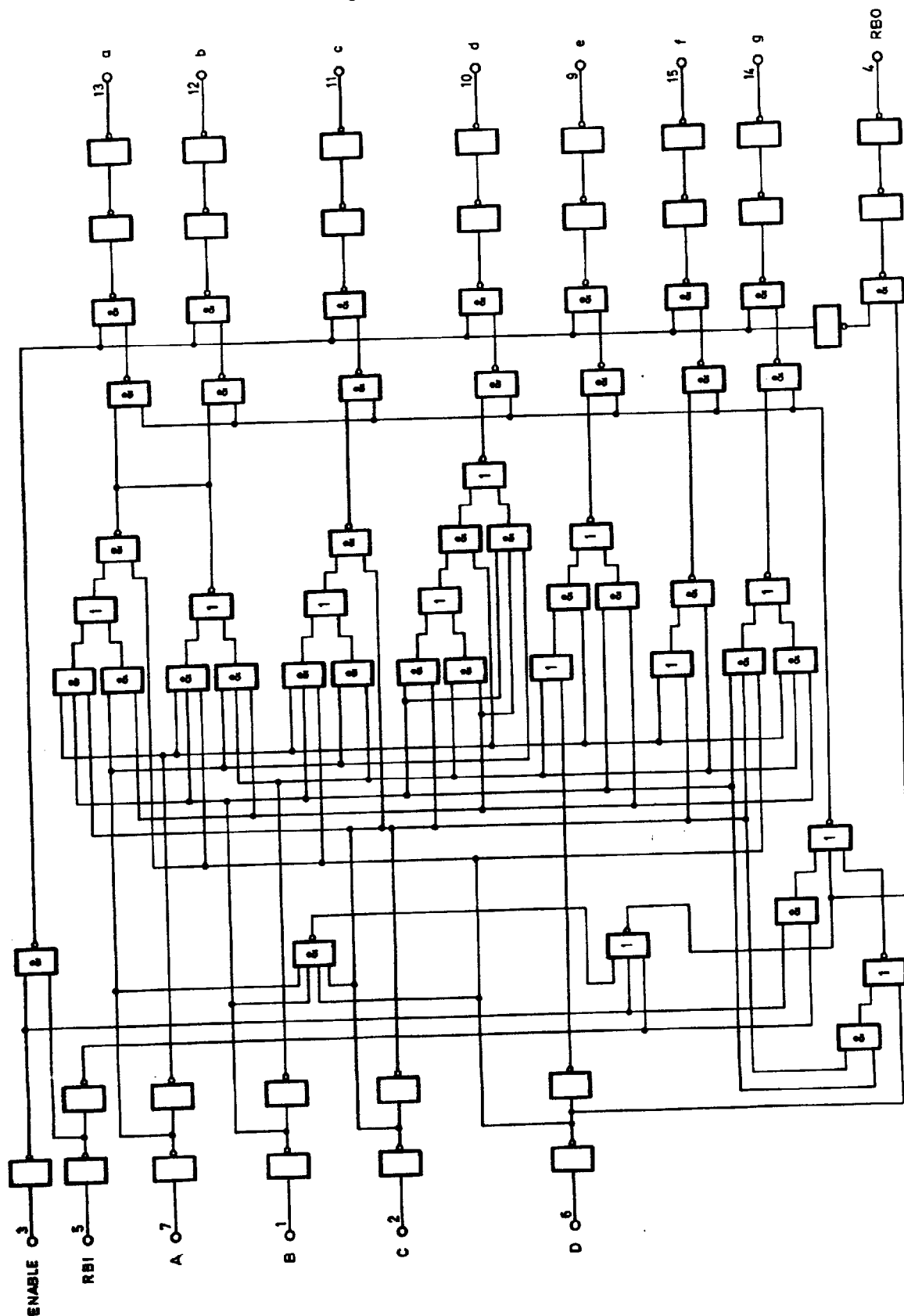


Figure 2

Signal waveform

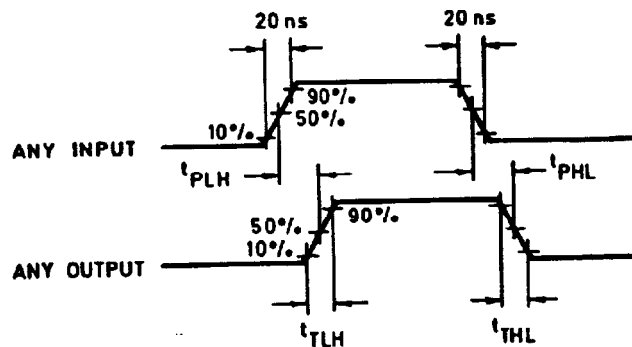


Figure 3

Marking

The following shall be marked on the device, in the following order of precedence, as space permits. All information, except the terminal marking shall appear on the primary package used as initial protection or wrapping for delivery:

- (1) Terminal identification
- (2) Type number
- (3) Operating temperature range (if not included in 2)
- (4) Quality assessment level applied
- (5) Screening class applied
- (6) Date-code (year-week defined by three or four figures)
- (7) Mark of conformity (CECC logo)
- (8) Manufacturers name or trade mark (may include factory code)
- (9) Factory identification code
- (10) Package materials
- (11) Caution label for devices susceptible to damage by electrostatic discharge
- (12) Optional tests